

<u>mailto:processchange@centralsemi.com</u>
https://www.centralsemi.com/process-change-notices

PCN #191 Notification Date: June 19, 2020

Product / Process Change Notice

Parts Affected:

Chip process CP771, P-channel MOSFETs, wafers and bare die.

Extent of Change:

The CP771 wafer process has been discontinued and is being replaced with the CP805 wafer process. See Figures 1 and 2 for details.

Reason for Change:

The CP771 wafer process has been replaced in order to enhance manufacturing process controls and device performance. This change will help ensure an undisrupted supply of product.

Effect of Change:

The CP805 wafer process meets all electrical specifications of the individual devices listed on the following page.

Qualification:

P/N: CP805 Chip Process Package: TO-220

N	lo.	Test	Conditions (Reference standards are in bold)	Qty	Pass/Fail	Test Results
1		Device Life Tests				
	А	High Temperature Gate Bias (HTGB)	T=150°C, t = 1000 hours 100% V_GS Negative Bias JESD22-A108	77	Pass	77/77
	В	High Temperature Gate Bias (HTGB)	T=150°C, t = 1000 hours 100% V_GS Positive Bias JESD22-A108	77	Pass	77/77
	С	High Temperature Reverse Bias (HTRB)	T=150°C, t = 1000 hours 100% V_DS JESD22-A108	77	Pass	77/77

Page 1 of 3



mailto:processchange@centralsemi.com https://www.centralsemi.com/process-change-notices

PCN #191 Notification Date: June 19, 2020

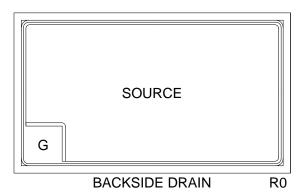
Effective Date of Change:

Existing inventory of chip process CP771 will be shipped until depleted.

Sample Availability:

Please contact your salesperson or manufacturer's representative for samples.

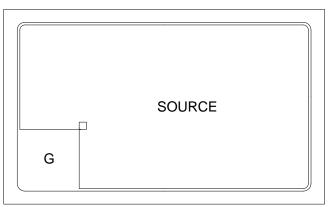
Figure 1: CP771 Chip Geometry (Discontinued)



Wafer Diameter: 8 inch
Die Size: 55 x 32 mils
Die Thickness: 7.5 mils
Bond Pad Size (Gate): 7.3 x 7.3 mils
Bond Pad Size (Source): 50 x 25 mils
Topside Metal: Al (40,000Å)

Backside Metal: Ti/Ni/Ag (1,000Å/3,000Å/10,000Å)

Figure 2: CP805 Chip Geometry



BACKSIDE DRAIN

Wafer Diameter: 8 inch

Die Size: 63.8 X 38.9 mils
Die Thickness: 5.5 mils
Bond Pad Size (Gate): 7.1 x 7.1 mils
Bond Pad Size (Source): 60.4 x 35.6 mils
Topside Metal: Al-Cu (40,000Å)

Backside Metal: Ti/Ni/Ag (1,000Å/3,000Å/10,000Å)

Part Numbers Affected:

CXDM4060P	CP771-CXDM4060P-CT
	CP771-CXDM4060P-WN

Page 2 of 3



<u>mailto:processchange@centralsemi.com</u> <u>https://www.centralsemi.com/process-change-notices</u>

PCN #191 Notification Date: June 19, 2020

As per JEDEC standard JESD46, Customer Notification of Product/Process Changes by Solid-State Suppliers, a lack of acknowledgement of a PCN within thirty (30) days constitutes acceptance of the change.

The undersigned acknowledges and accepts Central Semiconductor's Product/Process Change Notification (PCN).

Company Name:	
Address:	
Printed Name:	
Title:	
Signature:	
Date:	

Page 3 of 3